

Charlotte Zborowski

List of Publications by Year in descending order

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papers

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1478280

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1199470

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all docs

16
docs citations

16
times ranked

136
citing authors

#	ARTICLE	IF	CITATIONS
1	Effective inelastic scattering cross-sections for background analysis in HAXPES of deeply buried layers. Applied Surface Science, 2017, 402, 78-85.	3.1	33
2	Determination of the input parameters for inelastic background analysis combined with HAXPES using a reference sample. Applied Surface Science, 2018, 432, 60-70.	3.1	24
3	Analysis of buried interfaces in multilayer device structures with hard XPS (HAXPES) using a Cr K α source. Surface and Interface Analysis, 2018, 50, 1158-1162.	0.8	23
4	Theoretical study toward rationalizing inelastic background analysis of buried layers in XPS and HAXPES. Surface and Interface Analysis, 2019, 51, 857-873.	0.8	23
5	Quantitative determination of elemental diffusion from deeply buried layers by photoelectron spectroscopy. Journal of Applied Physics, 2018, 124, .	1.1	22
6	Quantitative spectromicroscopy from inelastically scattered photoelectrons in the hard X-ray range. Applied Physics Letters, 2016, 109, .	1.5	17
7	Surface analysis in the semiconductor industry: Present use and future possibilities. Surface and Interface Analysis, 2020, 52, 786-791.	0.8	4
8	Comparison and complementarity of QUASES-Tougaard and SESSA software. Applied Surface Science, 2022, 585, 152758.	3.1	3
9	Adsorptive behavior of phosphorus onto recycled waste biosolids after being acid leached from wastewater sludge. Chemical Engineering Journal Advances, 2022, 11, 100329.	2.4	3
10	Improved depth information from routine analysis of the inelastic background of XPS and HAXPES spectra using optimized two- and three-parameter cross-sections. Surface and Interface Analysis, 2022, 54, 433-441.	0.8	2
11	High-energy x-ray photoelectron spectroscopy spectra of TiO ₂ measured by Cr K α . Surface Science Spectra, 2022, 29, 014017.	0.3	2
12	HAXPES of GaN film on Si with Cr K α photons. Surface Science Spectra, 2021, 28, 014006.	0.3	1
13	High-energy x-ray photoelectron spectroscopy spectra of InP measured by Cr K α . Surface Science Spectra, 2022, 29, 014018.	0.3	1
14	High-energy x-ray photoelectron spectroscopy spectra of Al ₂ O ₃ measured by Cr K α . Surface Science Spectra, 2022, 29, 014021.	0.3	1
15	High-energy x-ray photoelectron spectroscopy spectra of HfO ₂ measured by Cr K α . Surface Science Spectra, 2022, 29, 014019.	0.3	1
16	High-energy x-ray photoelectron spectroscopy spectra of TiN measured by Cr K α . Surface Science Spectra, 2022, 29, 014016.	0.3	1